

Effect of matching errors on the precision of ratios in integrated circuits.

Premise:

Let us define the ratio:

$$r = \frac{R_1 + \dots + R_M}{R_{M+1} + \dots + R_{M+N}} \quad (1)$$

Where R is a quantity (e.g. the resistance) associated to a type of component (e.g. a resistor) and R_i are the value assumed by R on $N+M$ nominally identical components. Clearly, the nominal value of r is M/N .

Let us now consider a series of different runs for the same chip, and identify the runs with number j . With obvious notation, we will indicate the ratio r_j at run j as:

$$r_j = \frac{R_{1,j} + \dots + R_{M,j}}{R_{M+1,j} + \dots + R_{M+N,j}} \quad (2)$$

For each run we can consider that the values $R_{i,j}$ are the result of a stochastic process. We can define the mean $\langle R_j \rangle$ of that process. $\langle R_j \rangle$ can be regarded as the average of an infinite number of nominally identical components $R_{i,j}$, all produced in the same chip at run j . This is clearly an ideal operation, since the number of component that can be included into a single chip in a single run is finite and generally small. We also observe that $\langle R_j \rangle$ varies widely from run to run owing to process variations (global variations). We can write the $R_{i,j}$ values as:

$$R_{i,j} = \langle R_j \rangle + \delta R_{i,j} \quad (3)$$

It can be easily demonstrated that, if the mean $\langle R_j \rangle$ is really the limit of the average calculated on an ideally infinite number of components, the deviations $\delta R_{i,j}$ are uncorrelated, i.e. $\langle \delta R_{i,j} \cdot \delta R_{k,j} \rangle$ averaged over an infinite number of runs is zero.

Using (3) we can write the ratio (2) as:

$$r_j = \frac{(\langle R_j \rangle + \delta R_{1,j}) + \dots + (\langle R_j \rangle + \delta R_{M,j})}{(\langle R_j \rangle + \delta R_{M+1,j}) + \dots + (\langle R_j \rangle + \delta R_{M+N,j})} = \frac{M \langle R_j \rangle + \sum_{i=1}^M \delta R_{i,j}}{N \langle R_j \rangle + \sum_{i=M+1}^{M+N} \delta R_{i,j}} \quad (4)$$

which can be rewritten as:

$$r_j = \frac{M}{N} \frac{1 + \sum_{i=1}^M \frac{\delta R_{i,j}}{\langle R_j \rangle}}{1 + \sum_{i=M+1}^{M+N} \frac{\delta R_{i,j}}{\langle R_j \rangle}} \quad (5)$$

If
$$\sum_{i=1}^M \frac{\delta R_{i,j}}{\langle R_j \rangle} \ll 1 \quad \text{and} \quad \sum_{i=M+1}^{M+N} \frac{\delta R_{i,j}}{\langle R_j \rangle} \ll 1 \quad (8)$$

then, we can apply first order Taylor approximation and easily find that:

$$r_j \cong \frac{M}{N} \left(1 + \frac{\delta R_{i,j}}{M \langle R_j \rangle} - \sum_{i=M+1}^{M+N} \frac{\delta R_{i,j}}{N \langle R_j \rangle} \right) \quad (9)$$

Now, considering that $\delta R_{i,j}$ are uncorrelated, we find:

$$\frac{\sigma_r}{r_{nom}} \cong \sigma_{\frac{\delta R}{R}} \sqrt{\frac{1}{N} + \frac{1}{M}} \quad (10)$$

where r_{nom} is the nominal value of ratio r , i.e. M/N .

Eq. (10) relates the standard deviation of the relative error on the ratio r to the standard deviation of the relative mismatch error of the quantity R with respect of the average over a single run, $\langle R_j \rangle$. Since the data that is generally reported is the standard deviation of the relative *matching error* between two elements, ΔR , than we have to find a relationship between $\sigma_{\delta R}$ and $\sigma_{\Delta R}$.

Considering for simplicity two elements R_1 and R_2 , we can write:

$$\Delta R = R_{1,j} - R_{2,j} = \delta R_{1,j} - \delta R_{2,j} \quad (11)$$

Using the statistical independence of the terms $\delta R_{i,j}$, we get:

$$\sigma_{\Delta R}^2 = \sigma_{\delta R_1}^2 + \sigma_{\delta R_2}^2 = 2\sigma_{\delta R}^2 \quad (12)$$

With simple substitutions, we can rewrite (10) as:

$$\frac{\sigma_r}{r_{nom}} \cong \sigma_{\frac{\Delta R}{R}} \left[\frac{1}{\sqrt{2}} \sqrt{\frac{1}{N} + \frac{1}{M}} \right] \quad (13)$$